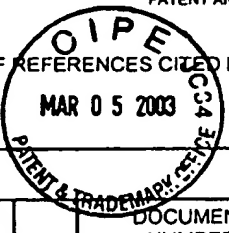


| Form PTO 1449 (Modified) | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY DOCKET NO. 0057-2362-2YY | | SERIAL NO. 09/176,315 | |
|--|----|---|----------|--------------------------------------|-----------------------|--------------------------|-------------------------------|
| LIST OF REFERENCES CITED BY APPLICANT  | | | | APPLICANT SHIGENOBU MAEDA, ET AL. | | | |
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| SWC | AA | 4,946,799 | 08/07/90 | Blake et al. | | | |
| | AB | | | | | | |
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| | AF | | | | | | |
| | AG | | | | | | |
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| | AJ | | | | | | |
| | AK | | | | | | |
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| OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.) | | | | | | | |
| SWC | AX | Modulationsdotierte Feldeffekttransistoren; Heiner HeiB; Dissertaton am Lehrstuhl für Halbleitertechnologie der TU München; eingereicht am 31.10.1996, pages 59 to 69 (with English abstract) | | | | | |
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| | AZ | These references are not in English, and the Examiner is unable to read them. SWC | | | | | |
| | AZ | | | | | | |
| Examiner CRANK | | | | Date Considered 4/28/03, 8/3/06 | | | |

* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.